Ref. Certif. No.

US/10717/ITS

IEC SYSTEM FOR MUTUAL RECOGNITION OF TEST CERTIFICATES FOR ELECTRICAL EQUIPMENT (IECEE) CB SCHEME

CB TEST CERTIFICATE

Product	Surface Area and Porosimetry Analyzer
Name and address of the applicant	Micromeritics Instrument Corporation 4356 Communications Drive Norcross, GA, 30093 United States of America
Name and address of the manufacturer	Micromeritics Instrument Corporation 4356 Communications Drive Norcross, GA, 30093 United States of America
Name and address of the factory *Note: When more than one factory, please report on page 2*	Micromeritics Instrument Corporation 4356 Communications Drive Norcross, GA, 30093 United States of America ☐ Additional information on page 2
Ratings and principal characteristics	100/115/230Vac, 50/60Hz, 800VA
Trademark / Brand (if any)	micromeritics
Customer's Testing Facility (CTF) Stage used	
Model / Type Ref.	ASAP 2425
Additional information (if necessary may also be reported on page 2)	☐ Additional information on page 2
A sample of the product was tested and found to be in conformity with	IEC 61010-1:2010/AMD1:2016, IEC 61010-2-010:2019, IEC 61010-2-081:2019 Comments: Refer to the Test Report for the Summary of Compliance with National Deviations
As shown in the Test Report Ref. No. which forms part of this Certificate	105996490ATL-001C, 105996490ATL-001D, 105996490ATL-001E

This CB Test Certificate is issued by the National Certification Body

Intertek Testing Services NA, Inc.
545 E. Algonquin Road , Arlington Heights
IL 60005
United States of America

Date: 2025-02-19

Signature: Matt Snyder Matthew Snyder